

STE110NS20FD

N-channel 200V - 0.022Ω - 110A - ISOTOP MESH OVERLAY™ Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STE110NS20FD	200V	<0.024Ω	110A

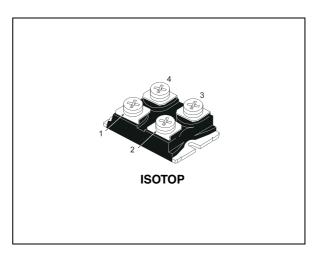
- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- ± 20V gate to source voltage rating
- Low intrinsic capacitance
- Fast body-drain diode:low trr, Qrr

Description

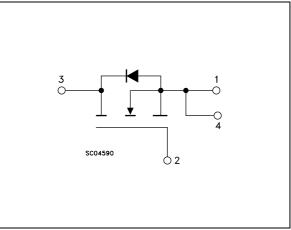
Using the latest high voltage MESH OVERLAY[™] process, STMicroelectronics has designed an advanced family of Power MOSFETs with outstanding performances. The new patented STrip layout coupled with the Company's proprietary edge termination structure, gives the lowest R_{DS(ON)} per area, exceptional avalanche and dv/dt capabilities and unrivalled gate charge and switching characteristics.

Applications

Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STE110NS20FD	E110NS20FD	ISOTOP	Tube

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Electrical ratings

Table 1.	Absolute maximum ratings		
Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	200	V
V _{DGR}	Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	200	V
V _{GS}	Gate- source voltage	±20	V
I _D	Drain current (continuos) at $T_C = 25^{\circ}C$	110	A
I _D	Drain current (continuos) at T _C = 100°C	69	А
I _{DM} ⁽¹⁾	Drain current (pulsed)	440	A
P _{TOT}	Total dissipation at $T_{C} = 25^{\circ}C$	500	W
	Derating factor	4	W/°C
dv/dt (2)	Peak diode recovery voltage slope	25	V/ns
V _{ISO}	Insulation winthstand voltage (AC-RMS)	2500	V
T _{stg}	Storage temperature	-65 to 150	°C
Тj	Max. operating junction temperature	150	°C

1. Pulse width limited by safe operating area

2. $I_{SD} \leq 110A$, di/dt $\leq 200A/\mu s$, $V_{DD} = 80\% V_{(BR)DSS}$

Table 2. Thermal resistance

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case Max	0.25	°C/W
Rthj-amb	Thermal resistance junction-ambient Max	30	°C/W
Τ _Ι	Maximum lead temperature for soldering purpose	300	°C

Table 3.Avalanche data

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T _j max)	110	A
E _{AS}	Single pulse avalanche energy (starting $T_j = 25 \text{ °C}$, $I_D = I_{AR}$, $V_{DD} = 50V$)	750	mJ



Electrical characteristics 2

(T_{CASE}=25°C unless otherwise specified)

Table 4.	On/off states					
Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{D} = 250 \mu A, V_{GS} = 0$	200			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = Max rating V _{DS} = Max rating, @125°C			10 100	μΑ μΑ
I _{GSS}	Gate body leakage current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10V, I _D = 50A		0.022	0.024	Ω

ble 4. On/off states

Table 5. Dynamic

	= jae					
Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max},$ $I_{D} = 50A$		30		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25V, f=1 MHz, V _{GS} =0		7900 1500 460		pF pF pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 100V, I_D = 100A, V_{GS} = 10V (see Figure 13)		360 35 135	504	nC nC nC

1. Pulsed: pulse duration=300µs, duty cycle 1.5%



	5					
Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	$V_{DD} = 100V, I_D = 50A$ $R_G = 4.7\Omega V_{GS} = 10V$ (see Figure 12)		40 130		ns ns
t _{r(Voff)} t _f t _c	Off-voltage rise time Fall time Cross-over time	$V_{DD} = 100V, I_D = 100A,$ $R_G = 4.7\Omega, V_{GS} = 10V$ (see Figure 12)		245 140 220		ns ns ns

Table 6.Switching times

Table 7. Source drain diode

Symbol	Parameter	Test condictions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current				110	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				440	Α
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 100A, V_{GS} = 0$			1.6	V
t _{rr} Q _{rr}	Reverse recovery time Reverse recovery charge	I_{SD} =100A, Tj=150°C di/dt = 100A/µs,		225 1.35 12		ns µC
IRRM	Reverse recovery current	V _{DD} =160V, (see Figure 17)		12		A

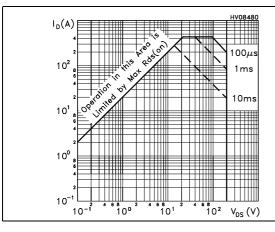
1. Pulse width limited by safe operating area

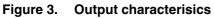
2. Pulsed: pulse duration=300µs, duty cycle 1.5%

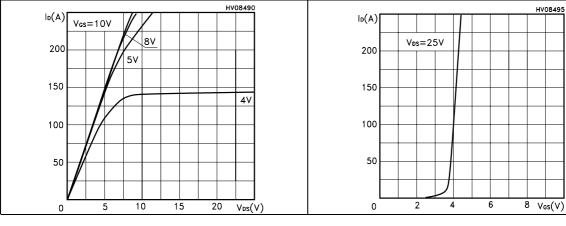
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2.1 Electrical characteristics (curves)

Figure 1. Safe operating area











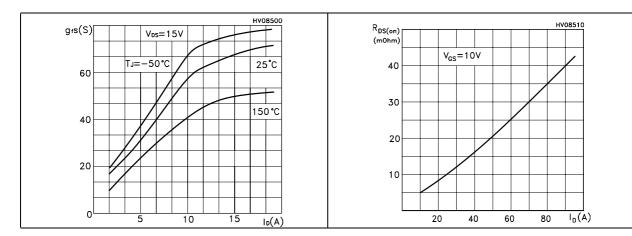
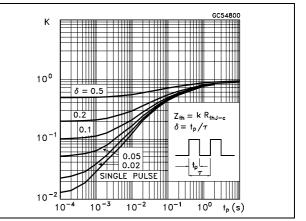




Figure 2.



Thermal impedance

HV08540

150 T√℃)

100

50

HV08520 $V_{GS}(V)$ C(pF) f=1MHz Vcs=0V Vps=160V 12 8000 ID=100A 9 6000 6 4000 2000 3 10 20 30 0 100 200 300 Qg(nC) 0

Gate charge vs gate-source voltage Figure 8. Capacitance variations Figure 7.

Figure 9. Normalized gate threshold voltage vs temperature

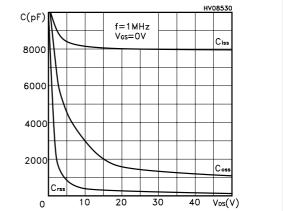


Figure 10. Normalized on resistance vs temperature

VGs=10∨ ID=50A

Ros(on)

(norm)

1.70

1.50

1.30

1.10

0.90

0

-50

0

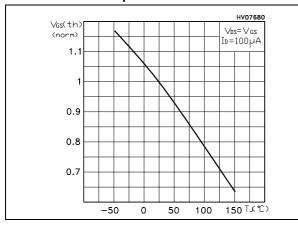
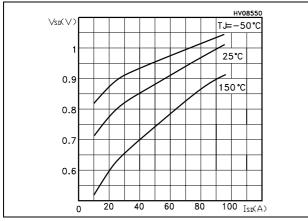


Figure 11. Source-drain diode forward characteristics





3 **Test circuit**

Figure 12. Switching times test circuit for resistive load

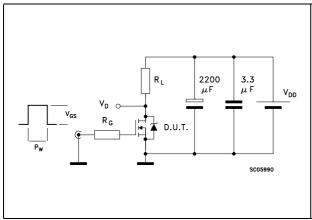
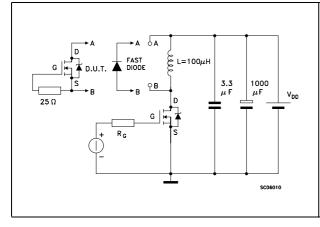


Figure 14. Test circuit for inductive load switching and diode recovery times





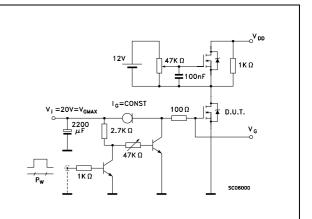


Figure 15. Unclamped inductive load test circuit

Figure 13. Gate charge test circuit



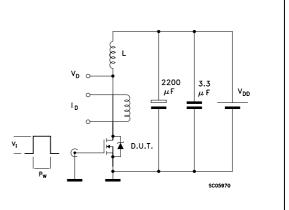
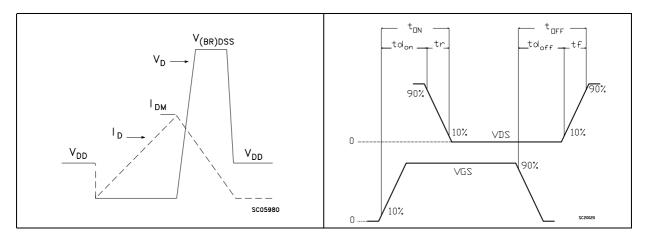


Figure 17. Switching time waveform



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4 Package mechanical data

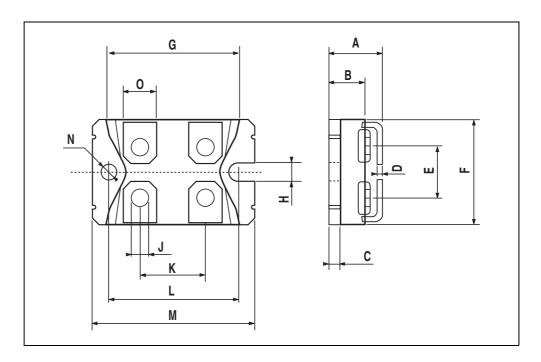
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at : *www.st.com*



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DIM.		mm			inch	
Diwi.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	11.8		12.2	0.466		0.480
В	8.9		9.1	0.350		0.358
С	1.95		2.05	0.076		0.080
D	0.75		0.85	0.029		0.033
Е	12.6		12.8	0.496		0.503
F	25.15		25.5	0.990		1.003
G	31.5		31.7	1.240		1.248
н	4			0.157		
J	4.1		4.3	0.161		0.169
к	14.9		15.1	0.586		0.594
L	30.1		30.3	1.185		1.193
М	37.8		38.2	1.488		1.503
Ν	4			0.157		
0	7.8		8.2	0.307		0.322

ISOTOP MECHANICAL DATA



5 Revision history

Table 8. Revision history

Date	Revision	Changes
12-May-2006	3	New template



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